

P-Channel 12 V (D-S) MOSFET

PRODUCT SUMMARY

V_{DS} (V)	$R_{DS(on)}$ (Ω)	I_D (A) ^a	Q_g (Typ.)
- 12	0.034 at $V_{GS} = -4.5$ V	- 4	14.1 nC
	0.046 at $V_{GS} = -2.5$ V	- 4	
	0.070 at $V_{GS} = -1.8$ V	- 4	
	0.110 at $V_{GS} = -1.5$ V	- 4	

FEATURES

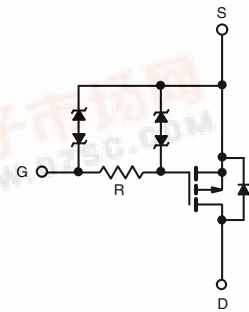
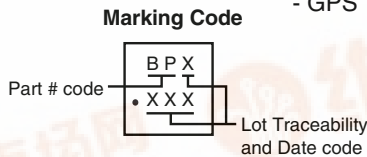
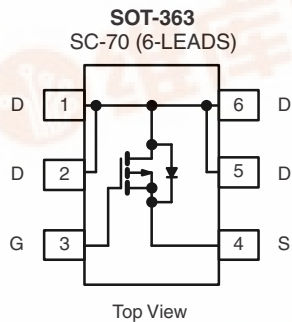
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- Typical ESD Performance 1500 V
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC



RoHS
COMPLIANT
HALOGEN
FREE

APPLICATIONS

- Load Switch, PA Switch and Battery Switch for Portable Devices
 - Cellular Phone
 - DSC
 - Portable Game Console
 - MP3
 - GPS



Ordering Information: Si1401EDH-T1-GE3 (Lead (Pb)-free and Halogen-free)

P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	- 12	V
Gate-Source Voltage	V_{GS}	± 10	
Continuous Drain Current ($T_J = 150^\circ\text{C}$)	I_D	$T_C = 25^\circ\text{C}$ - 4 ^a	A
		$T_C = 70^\circ\text{C}$ - 4 ^a	
		$T_A = 25^\circ\text{C}$ - 4 ^{a, b, c}	
		$T_A = 70^\circ\text{C}$ - 4 ^{a, b, c}	
Pulsed Drain Current	I_{DM}	- 25	
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$ - 2.3	
		$T_A = 25^\circ\text{C}$ - 1.3 ^{b, c}	
Maximum Power Dissipation	P_D	$T_C = 25^\circ\text{C}$ 2.8	W
		$T_C = 70^\circ\text{C}$ 1.8	
		$T_A = 25^\circ\text{C}$ 1.6 ^{b, c}	
		$T_A = 70^\circ\text{C}$ 1.0 ^{b, c}	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to 150	$^\circ\text{C}$
Soldering Recommendations (Peak Temperature)		260	

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	R_{thJA}	60	80	$^\circ\text{C/W}$
Maximum Junction-to-Foot (Drain)	R_{thJF}	34	45	

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. $t = 5$ s.

d. Maximum under steady state conditions is 125 $^\circ\text{C/W}$.

Si1401EDH

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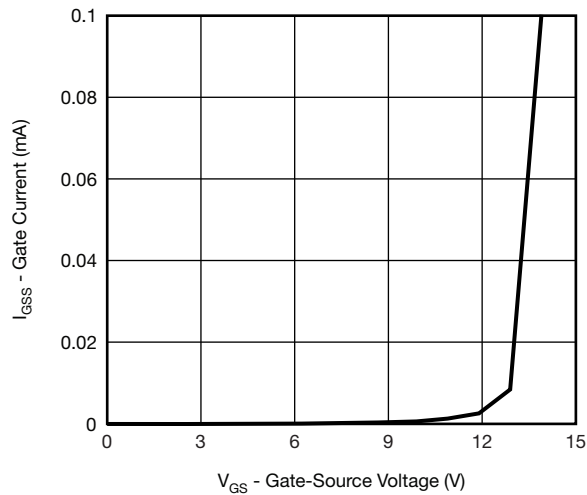
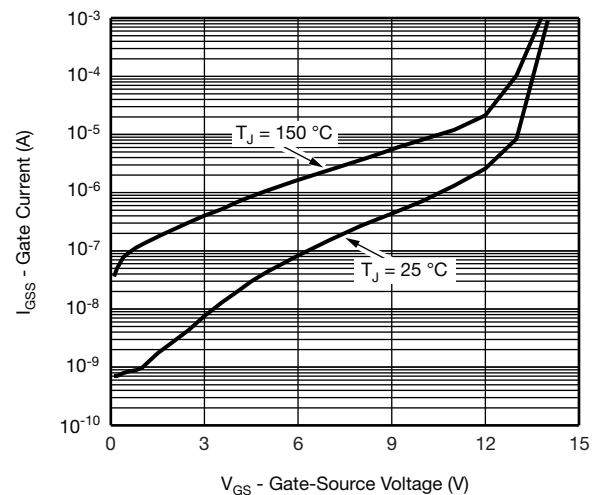
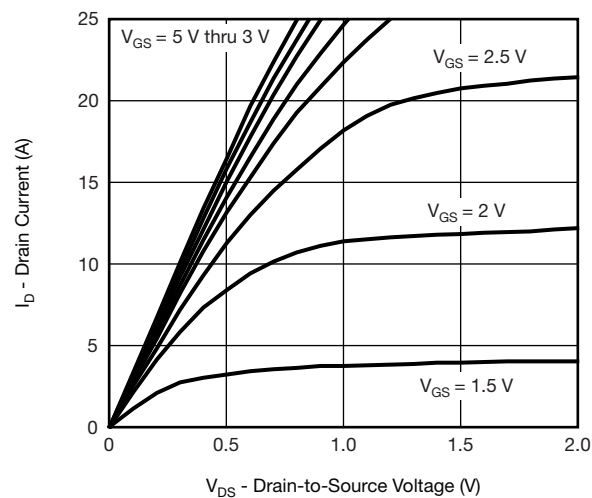
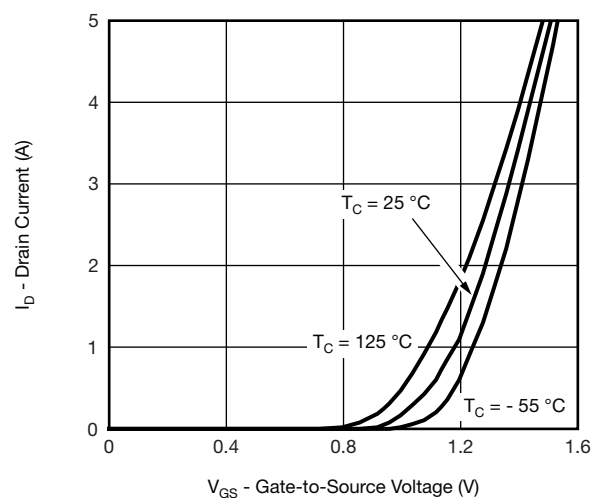
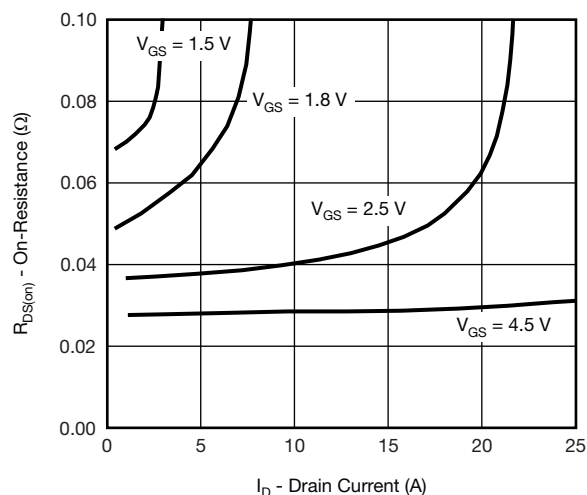
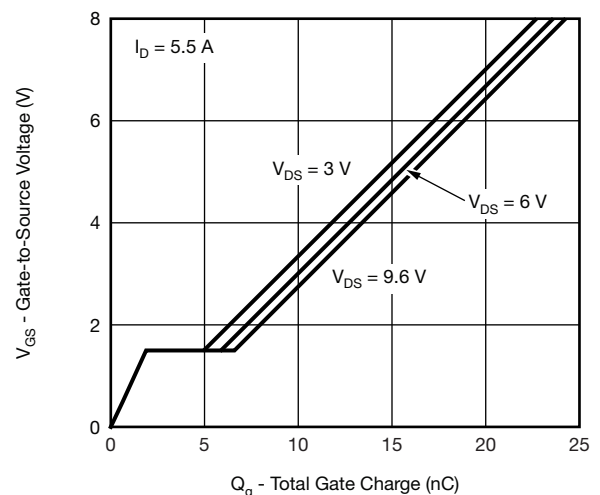
SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 12			V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = - 250 μA		- 5.2		mV/°C	
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J			2.5			
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = - 250 μA	- 0.4		- 1	V	
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 8 V			± 5	μA	
		V _{DS} = 0 V, V _{GS} = ± 4.5 V			± 1		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 12 V, V _{GS} = 0 V			- 1		
		V _{DS} = - 12 V, V _{GS} = 0 V, T _J = 55 °C			- 10		
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≤ - 5 V, V _{GS} = - 10 V	- 15			A	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 5.5 A		0.028	0.034	Ω	
		V _{GS} = - 2.5 V, I _D = - 4.8 A		0.038	0.046		
		V _{GS} = - 1.8 V, I _D = - 1.4 A		0.053	0.070		
		V _{GS} = - 1.5 V, I _D = - 0.9 A		0.072	0.110		
Forward Transconductance ^a	g _{fs}	V _{DS} = - 6 V, I _D = - 5.5 A		16		S	
Dynamic ^b							
Total Gate Charge	Q _g	V _{DS} = - 6 V, V _{GS} = - 8 V, I _D = - 5.5 A		24	36	nC	
Gate-Source Charge		V _{DS} = - 6 V, V _{GS} = - 4.5 V, I _D = - 5.5 A		14.1	22		
			Q _{gs}		1.9		
Gate-Drain Charge	Q _{gd}			4			
Gate Resistance	R _g	f = 1 MHz	0.08	0.42	0.84	kΩ	
Turn-On Delay Time	t _{d(on)}	V _{DD} = - 6 V, R _L = 1.4 Ω I _D ≅ - 4.4 A, V _{GEN} = - 4.5 V, R _g = 1 Ω		160	240	ns	
Rise Time	t _r			420	630		
Turn-Off Delay Time	t _{d(off)}			1325	1990		
Fall Time	t _f			985	1480		
Turn-On Delay Time	t _{d(on)}	V _{DD} = - 6 V, R _L = 1.4 Ω I _D ≅ - 4.4 A, V _{GEN} = - 8 V, R _g = 1 Ω		72	110		
Rise Time	t _r			210	320		
Turn-Off Delay Time	t _{d(off)}			2100	3150		
Fall Time	t _f			1015	1525		
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 2.3	A	
Pulse Diode Forward Current	I _{SM}				- 25		
Body Diode Voltage	V _{SD}	I _S = - 5.5 A, V _{GS} = 0 V		- 0.85	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	I _F = - 5.5 A, dI/dt = 100 A/μs, T _J = 25 °C		27	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			12	25	nC	
Reverse Recovery Fall Time	t _a			10		ns	
Reverse Recovery Rise Time	t _b			17			

Notes:

a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.

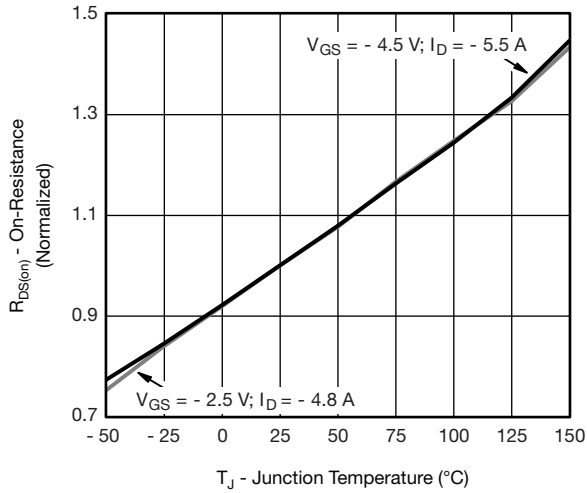
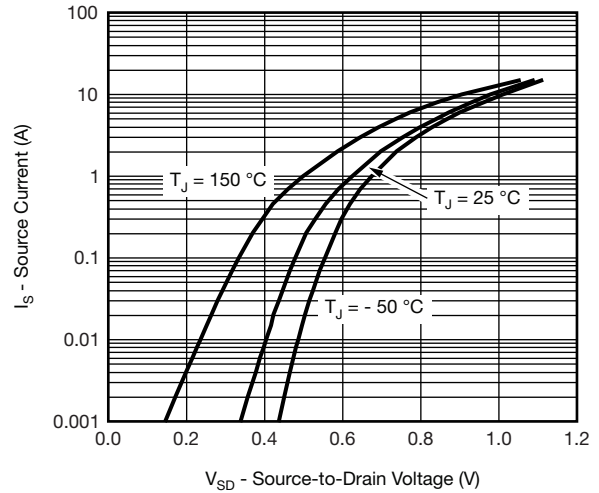
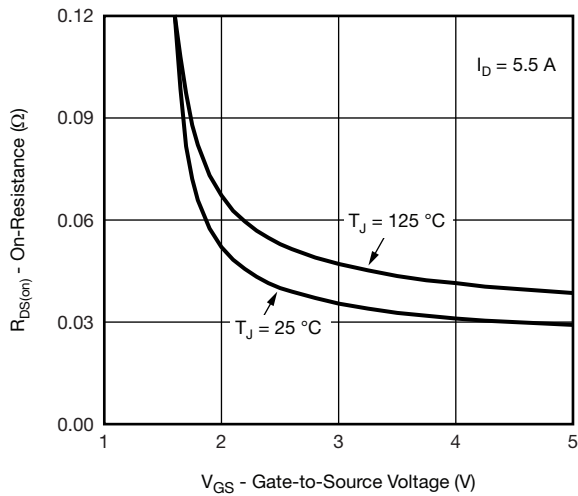
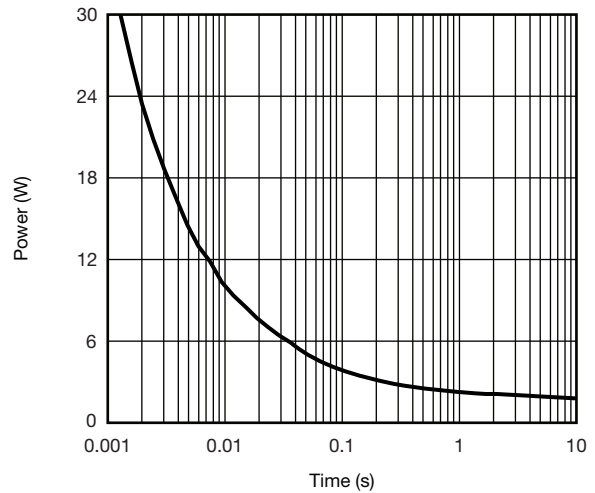
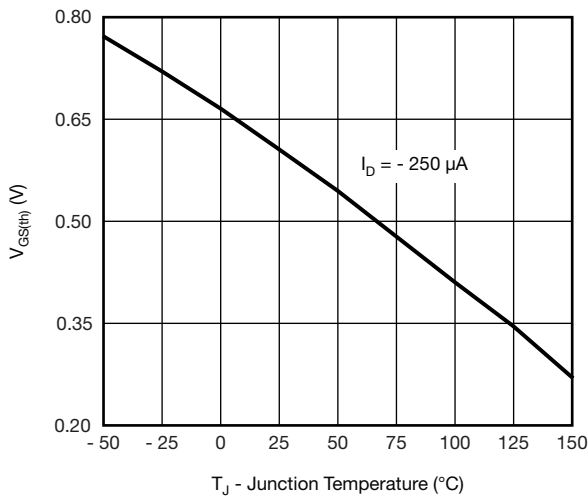
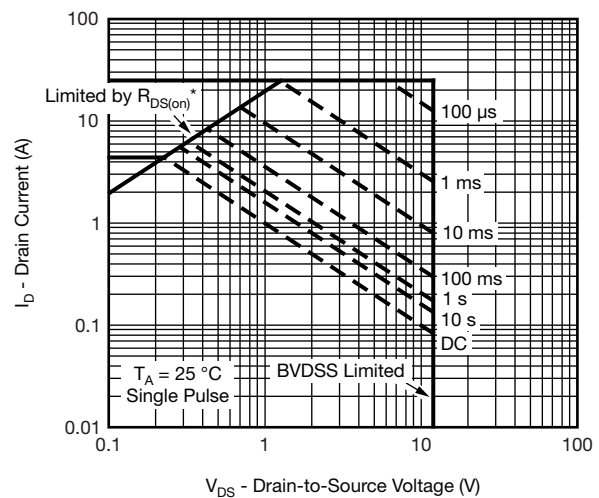
b. Guaranteed by design, not subject to production testing.

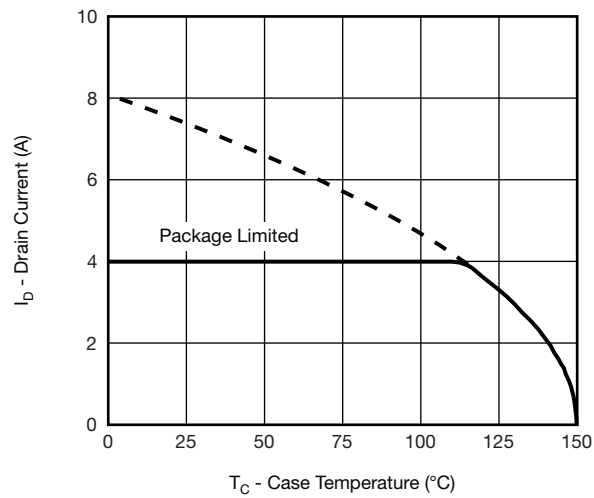
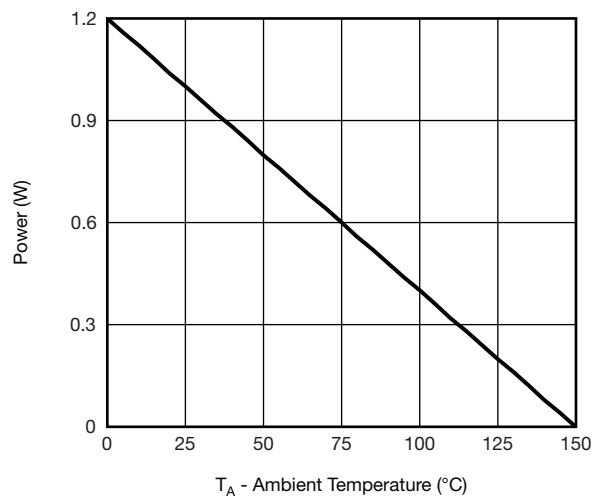
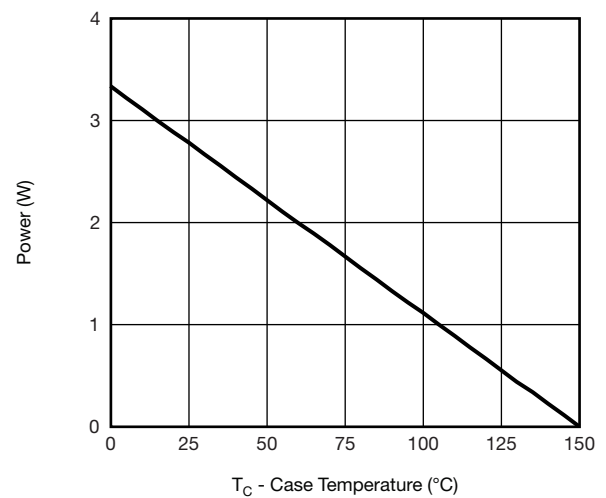
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Gate Current vs. Gate-Source Voltage

Gate Current vs. Gate-Source Voltage

Output Characteristics

Transfer Characteristics

On-Resistance vs. Drain Current

Gate Charge

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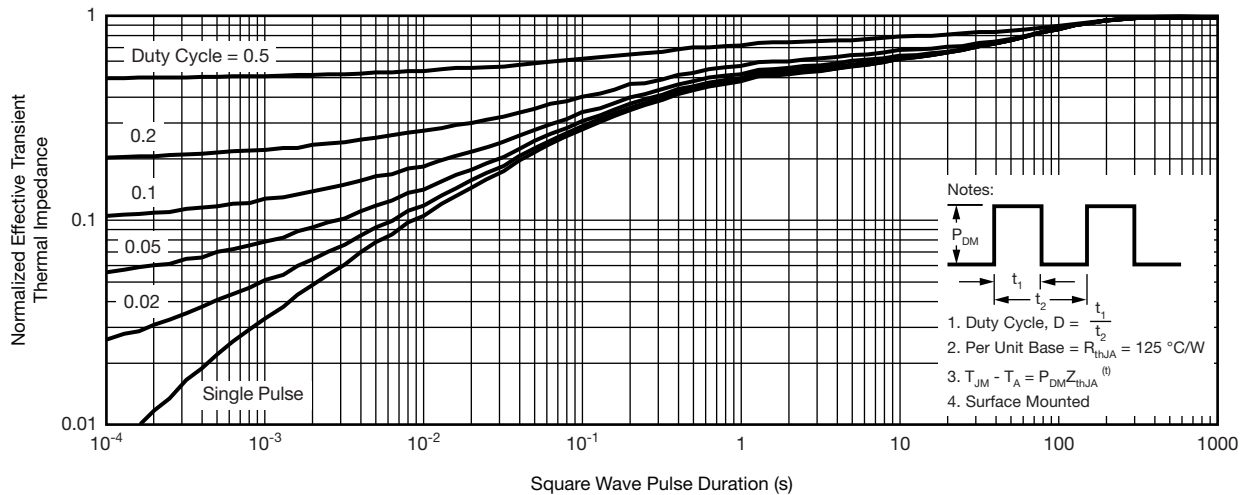
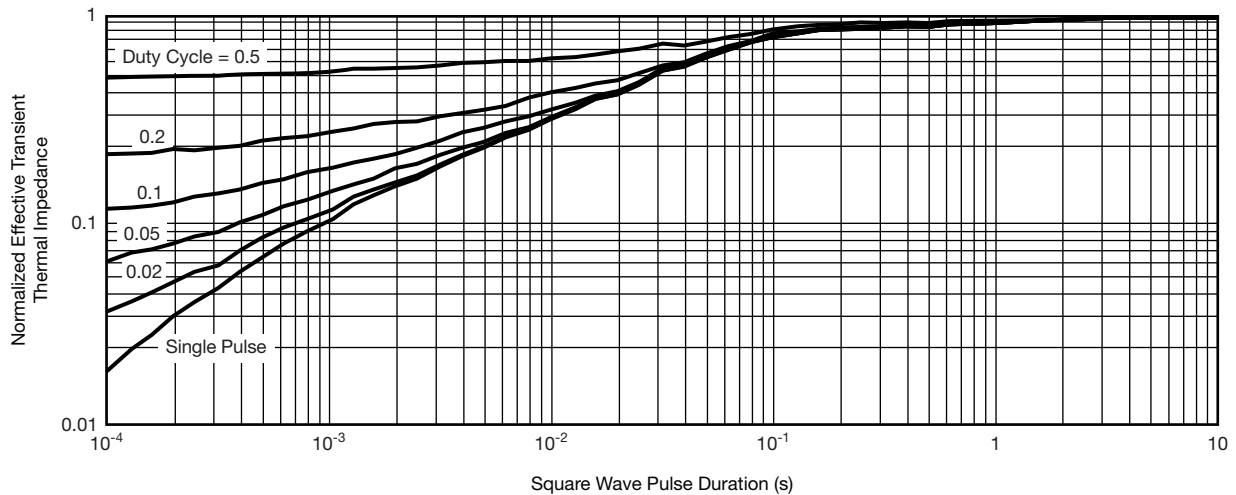
**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted**On-Resistance vs. Junction Temperature****Source-Drain Diode Forward Voltage****On-Resistance vs. Gate-to-Source Voltage****Single Pulse Power, Junction-to-Ambient****Threshold Voltage*** V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified**Safe Operating Area, Junction-to-Ambient**

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Current Derating*

Power Derating, Junction-to-Ambient

Power Derating, Junction-to-Foot

* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted**Normalized Thermal Transient Impedance, Junction-to-Ambient****Normalized Thermal Transient Impedance, Junction-to-Foot**

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